







SN74HCS373

ZHCSP26A - OCTOBER 2021 - REVISED DECEMBER 2022

具有施密特触发输入和三态输出的 SN74HCS373 八路透明 D 型锁存器

1 特性

- 宽工作电压范围: 2V 至 6V
- 施密特触发输入可实现慢速或高噪声输入信号
- 低功耗
 - I_{CC} 典型值为 100nA
 - 输入漏电流典型值为 ±100nA
- 电压为 6V 时,输出驱动为 ±7.8mA
- 更宽泛的工作环境温度范围: -40°C至+125°C, T_A

2 应用

- 并行数据存储
- 数字总线缓冲器

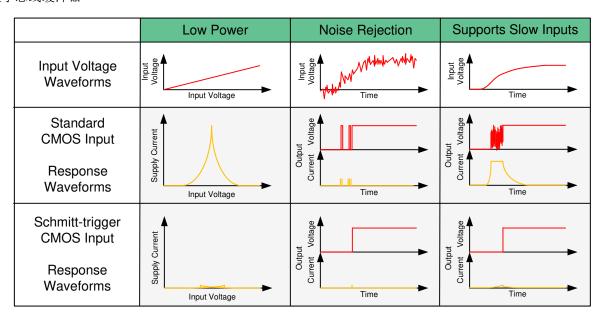
3 说明

SN74HCS373 包含八路 D 类锁存器。所有输入均包括 施密特触发架构。所有通道共享锁存器使能 (LE) 输入 和输出使能 (OE) 输入。

器件信息

	ישי בון ון אור	
器件型号	封装 ⁽¹⁾	封装尺寸(标称值)
SN74HCS373	RKS (VQFN, 20)	4.50 mm × 2.50 mm
	DGS (VSSOP, 20)	5.10 mm × 3.00 mm

(1) 如需了解所有可用封装,请见数据表末尾的可订购产品附录。



施密特触发输入的优势



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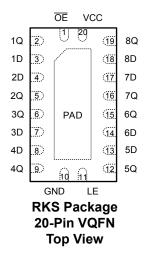
4 Revision History 注:以前版本的页码可能与当前版本的页码不同

С	Changes from Revision * (October 2021) to Revision A (December 2022)	Page
•	将"应用信息"更改为"量产数据"	
•	向器件信息表添加了 DGS 器件	1
•	Added DGS (VSSOP) Package Information	3
•	Added DGS package Thermal Information	4
•	Updated the Detailed Design Procedure section	13

Product Folder Links: SN74HCS373



5 Pin Configuration and Functions



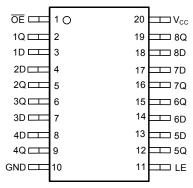


图 5-1. DGS Package 20-Pin VSSOP Top View

Pin Functions

PIN I/O DESCRIPTION		1/0	DESCRIPTION	
		DESCRIPTION		
ŌĒ	1	Input	Output enable, active low	
1Q	2	Output	utput for channel 1	
1D	3	Input	Input for channel 1	
2D	4	Input	Input for channel 2	
2Q	5	Output	Output for channel 2	
3Q	6	Output	Output for channel 3	
3D	7	Input	Input for channel 3	
4D	8	Input	Input for channel 4	
4Q	9	Output	Output for channel 4	
GND	10	_	Ground	
LE	11	Input	Latch enable	
5Q	12	Output	Output for channel 5	
5D	13	Input	Input for channel 5	
6D	14	Input	Input for channel 6	
6Q	15	Output	Output for channel 6	
7Q	16	Output	Output for channel 7	
7D	17	Input	Input for channel 7	
8D	18	Input	Input for channel 8	
8Q	19	Output	Output for channel 8	
V _{CC}	20	_	Postive supply	
Therma	al Pad ⁽¹⁾	_	The thermal pad can be connect to GND or left floating. Do not connect to any other signal or supply.	

(1) RKS package only.

English Data Sheet: SCLS878



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		- 0.5	7	V
I _{IK}	Input clamp current ⁽²⁾ $V_I < 0$ or $V_I > V_{CC}$			±20	mA
I _{OK}	Output clamp current ⁽²⁾	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±35	mA
I _{CC}	Continuous current through V _{CC} or GND	·		±70	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		- 65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.2 ESD Ratings

				VALUE	UNIT
V _(ESD)	V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 ⁽¹⁾	±4000	V
	Lieutiostatic discriarge	Charged-device model (CDM), per ANSI/ESDA/ JEDEC JS-002 ⁽²⁾	±1500	V	

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V _{CC}	Supply voltage	2	6	V
VI	Input voltage	0	V _{CC}	V
Vo	Output voltage	0	V _{CC}	V
T _A	Ambient temperature	- 40	125	°C

6.4 Thermal Information

THERMAL METRIC(1)		SN74H		
		RKS (VQFN)	DGS (VSSOP)	UNIT
		20 PINS	20 PINS	
R ₀ JA	Junction-to-ambient thermal resistance	83.2	130.6	°C/W
R _{θ JC(top)}	Junction-to-case (top) thermal resistance	82.6	68.7	°C/W
R ₀ JB	Junction-to-board thermal resistance	57.4	85.4	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	14.5	10.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	56.4	85.0	°C/W
R _{θ JC(bot)}	Junction-to-case (bottom) thermal resistance	40.0	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.5 Electrical Characteristics

over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted).

	PARAMETER	TEST CC	NDITIONS	V _{cc}	MIN	TYP	MAX	UNIT		
				2 V	0.7		1.5			
V_{T+}	Positive switching threshold			4.5 V	1.7		3.15	V		
				6 V	2.1		4.2			
				2 V	0.3	-	1			
V _{T-}	Negative switching threshold			4.5 V	0.9		2.2	V		
				6 V	1.2		3			
				2 V	0.2		1			
ΔV _T	Hysteresis (V _{T+} - V _{T-})			4.5 V	0.4		1.4	V		
				6 V	0.6	-	1.6			
	High-level output voltage				I _{OH} = -20 μA	2 V to 6 V	V _{CC} - 0.1	V _{CC} - 0.002		
V _{OH}		$V_I = V_{IH}$ or V_{IL}	I _{OH} = -6 mA	4.5 V	4	4.3		v		
			I _{OH} = -7.8 mA	6 V	5.4	5.75				
			I _{OL} = 20 μA	2 V to 6 V		0.002	0.1			
V _{OL}	Low-level output voltage	$V_I = V_{IH}$ or V_{IL}	I _{OL} = 6 mA	4.5 V		0.18	0.3	V		
			I _{OL} = 7.8 mA	6 V		0.22	0.33			
I _I	Input leakage current	$V_I = V_{CC}$ or 0		6 V		±100	±1000	nA		
I _{CC}	Supply current	$V_I = V_{CC}$ or 0, $I_O = 0$		6 V		0.1	2	μA		
Ci	Input capacitance			2 V to 6 V			5	pF		

6.6 Timing Characteristics

over operating free-air temperature range (unless otherwise noted), C_L = 50 pF

	PARAMETER	CONDITION	V _{cc}	MIN MA	X UNIT
			2 V	12	
t _w	Pulse duration	LE high	4.5 V	6	ns
			6 V	6	
		Data before LE ↓	2 V	18	
t _{su}	Setup time		4.5 V	6	ns
			6 V	6	
			2 V	0	
t _h	Hold time, Data before LE ↓		4.5 V	0	ns
			6 V	0	

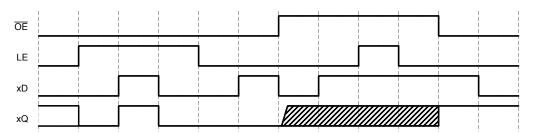


图 6-1. Timing diagram

6.7 Switching Characteristics

over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted). See *Parameter Measurement Information*. C_L = 50 pF.

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	MIN TYP	MAX	UNIT
				2 V	14.6	19.4	
t _t	Transition-time		Any Q	4.5 V	7.7	9.6	ns
				6 V	7.4	10.4	
				2 V	24.5	33	
		D	Q	4.5 V	9.9	14	
	Propogation delay			6 V	9.6	11	ns
t _{pd}			Any Q	2 V	24.5	33	
		LE		4.5 V	9.9	14	
				6 V	9.6	11	
				2 V	15	44	
t _{en}	Enable time	ŌĒ	Any Q	4.5 V	7	22	ns
				6 V	6	18	
			Any Q	2 V	12	30	
t _{dis}	Disable time	ŌĒ	Any Q	4.5 V	9	20	ns
			Any Q	6 V	8	19	

6.8 Operating Characteristics

over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted).

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{pd}	Power dissipation capacitance per gate	No load		20		pF

Product Folder Links: SN74HCS373

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6.9 Typical Characteristics

 $T_A = 25^{\circ}C$

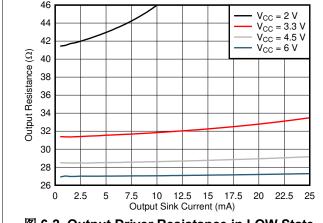


图 6-2. Output Driver Resistance in LOW State

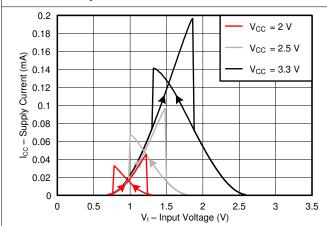


图 6-4. Supply Current Across Input Voltage, 2-, 2.5-, and 3.3-V Supply

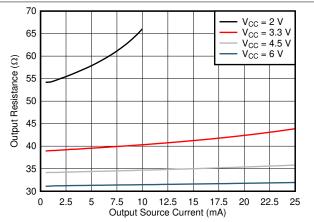


图 6-3. Output Driver Resistance in HIGH State

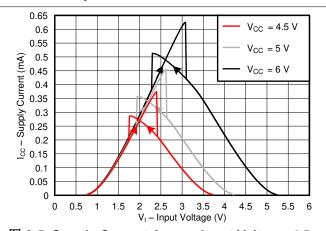


图 6-5. Supply Current Across Input Voltage, 4.5-, 5-, and 6-V Supply

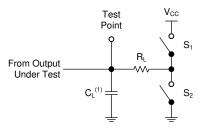


7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_t < 2.5 ns.

For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C_L includes probe and test-fixture capacitance.

图 7-1. Load Circuit for 3-State Outputs

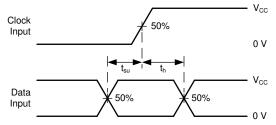


图 7-3. Voltage Waveforms, Setup and Hold Times

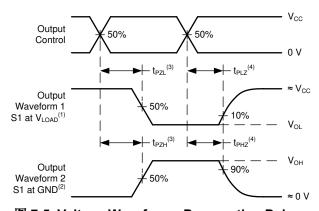


图 7-5. Voltage Waveforms Propagation Delays

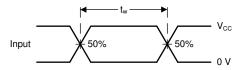
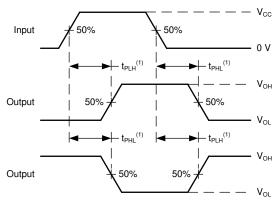
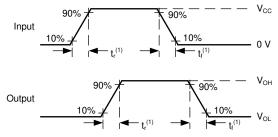


图 7-2. Voltage Waveforms, Pulse Duration



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

图 7-4. Voltage Waveforms Propagation Delays



(1) The greater between t_r and t_f is the same as t_t .

图 7-6. Voltage Waveforms, Input and Output
Transition Times

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8 Detailed Description

8.1 Overview

The SN74HCS373 contains eight D-type latches. All inputs include Schmitt-trigger architecture. All channels share a latch enable (LE) and output enable (OE) input.

When the latch is enabled (LE is high), data is allowed to pass through from the D inputs to the Q outputs.

When the latch is disabled (LE is low), the Q outputs hold the last state they had regardless of changes at the D inputs.

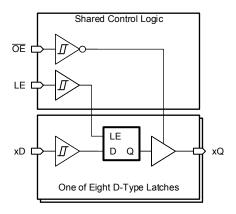
If the latch enable (LE) input is held low during startup, the output state of all channels is unknown until the latch enable (LE) input is driven high with valid input signals at all data (D) inputs.

When the outputs are enabled (OE is low), the outputs are actively driving low or high.

When the outputs are disabled (OE is high), the outputs are set into the high-impedance state.

The active low output enable (\overline{OE}) does not have any impact on the stored state in the latches.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Balanced CMOS 3-State Outputs

This device includes balanced CMOS 3-State outputs. The three states that these outputs can be in are driving high, driving low, and high impedance. The term "balanced" indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

When placed into the high-impedance mode, the output will neither source nor sink current, with the exception of minor leakage current as defined in the *Electrical Characteristics* table. In the high-impedance state, the output voltage is not controlled by the device and is dependent on external factors. If no other drivers are connected to the node, then this is known as a floating node and the voltage is unknown. A pull-up or pull-down resistor can be connected to the output to provide a known voltage at the output while it is in the high-impedance state. The value of the resistor will depend on multiple factors, including parasitic capacitance and power consumption limitations. Typically, a 10 k Ω resistor can be used to meet these requirements.

Unused 3-state CMOS outputs should be left disconnected.

English Data Sheet: SCLS878

8.3.2 CMOS Schmitt-Trigger Inputs

This device includes inputs with the Schmitt-trigger architecture. These inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics* table from the input to ground. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings* table, and the maximum input leakage current, given in the *Electrical Characteristics* table, using Ohm's law $(R = V \div I)$.

The Schmitt-trigger input architecture provides hysteresis as defined by ΔV_T in the *Electrical Characteristics* table, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs with slow transitioning signals will increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in Electrical Placement of Clamping Diodes for Each Input and Output.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

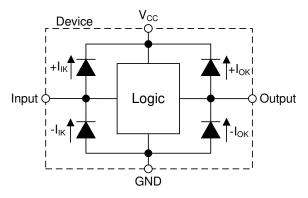


图 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

8.4 Device Functional Modes

表 8-1. Function Table

	OUTPUT ⁽²⁾		
ŌĒ	LE	Q	
L	Н	L	L
L	Н	Н	Н
L	L	Х	Q ₀ (3)
Н	Х	Х	Z

 L = input low, H = input high, ↑ = input transitioning from low to high, ↓ = input transitioning from high to low, X = don't care

Product Folder Links: SN74HCS373

- (2) L = output low, H = output high, Q₀ = previous state, Z = high impedance
- (3) At startup, Q₀ is unknown



9 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

In this application, the SN74HCS373 is used to control an 8-bit data bus.

Outputs can be held in the high-impedance state, held in the last known state, or change together with the data inputs, depending on the control inputs at LE and $\overline{\text{OE}}$ coming from the bus controller.

9.2 Typical Application

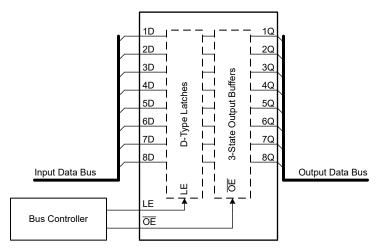


图 9-1. Typical Application Block Diagram

9.2.1 Design Requirements

9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74HCS373 plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74HCS373 plus the maximum supply current, I_{CC}, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74HCS373 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The SN74HCS373 can drive a load with total resistance described by $R_L \geqslant V_O / I_O$, with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

9.2.1.2 输入注意事项

输入信号必须超过 $V_{t-(min)}$ 才能被视为逻辑低电平,超过 $V_{t+(max)}$ 才能被视为逻辑高电平。不要超过*绝对最大额定值* 中的最大输入电压范围。

未使用的输入必须端接至 V_{CC} 或地。如果输入完全不使用,则可以直接端接未使用的输入,如果有时要使用输入,但并非始终使用,则可以使用上拉或下拉电阻器连接输入。上拉电阻用于默认高电平状态,下拉电阻用于默认低电平状态。控制器的驱动电流、进入 SN74HCS373 的漏电流(如*电气特性* 中所规定)以及所需输入转换率会限制电阻大小。由于这些因素,通常使用 10k Ω 的电阻值。

SN74HCS373 由于具有施密特触发输入,因而没有输入信号转换速率要求。

具有施密特触发输入的另一个优势是能够抑制噪声。振幅足够大的噪声仍然会导致问题。要了解噪声大到什么程度才是过大,请参考*电气特性* 中的 $\Delta V_{T(min)}$ 。此迟滞值将提供峰峰值限制。

与标准 CMOS 输入不同,施密特触发输入可以保持在任何有效值,而不会导致功耗大幅增加。将输入保持在 V_{CC} 或地以外的值所导致的典型附加电流绘制在 典型特性 中。

有关此器件的输入的附加信息,请参阅特性描述部分。

English Data Sheet: SCLS878

9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

9.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; it will, however, ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HCS373 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)})$ Ω . This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation.

9.2.3 Application Curve

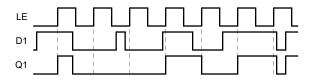


图 9-2. Example Timing Diagram for One Channel

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in given example layout image.

11 Layout

11.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC}, whichever makes more sense for the logic function or is more convenient.

11.2 Layout Example

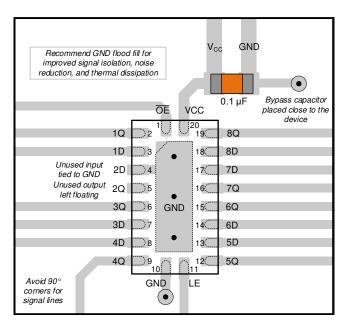


图 11-1. Example layout for the SN74HCS373 in the RKS Package

English Data Sheet: SCLS878

12 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, HCMOS Design Considerations application report (SCLA007)
- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report (SDYA009)
- · Texas Instruments, Designing With Logic application report

12.2 接收文档更新通知

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ESD 的损坏小至导致微小的性能降级,大至整个器件故障。精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

12.6 术语表

TI术语表本术语表列出并解释了术语、首字母缩略词和定义。

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13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

English Data Sheet: SCLS878

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74HCS373DGSR	Active	Production	VSSOP (DGS) 20	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HS373
SN74HCS373DGSR.A	Active	Production	VSSOP (DGS) 20	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HS373
SN74HCS373RKSR	Active	Production	VQFN (RKS) 20	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	HCS373
SN74HCS373RKSR.A	Active	Production	VQFN (RKS) 20	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	HCS373

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN74HCS373:

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 9-Nov-2025

Automotive: SN74HCS373-Q1

NOTE: Qualified Version Definitions:

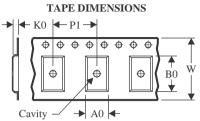
• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

www.ti.com 23-Jul-2025

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

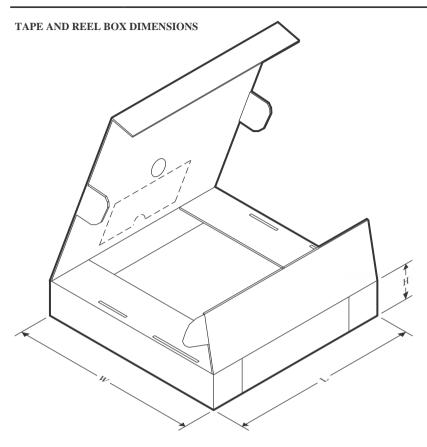


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HCS373DGSR	VSSOP	DGS	20	5000	330.0	16.4	5.4	5.4	1.45	8.0	16.0	Q1
SN74HCS373RKSR	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 23-Jul-2025



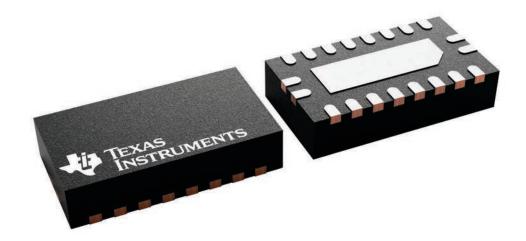
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HCS373DGSR	VSSOP	DGS	20	5000	353.0	353.0	32.0
SN74HCS373RKSR	VQFN	RKS	20	3000	210.0	185.0	35.0

2.5 x 4.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

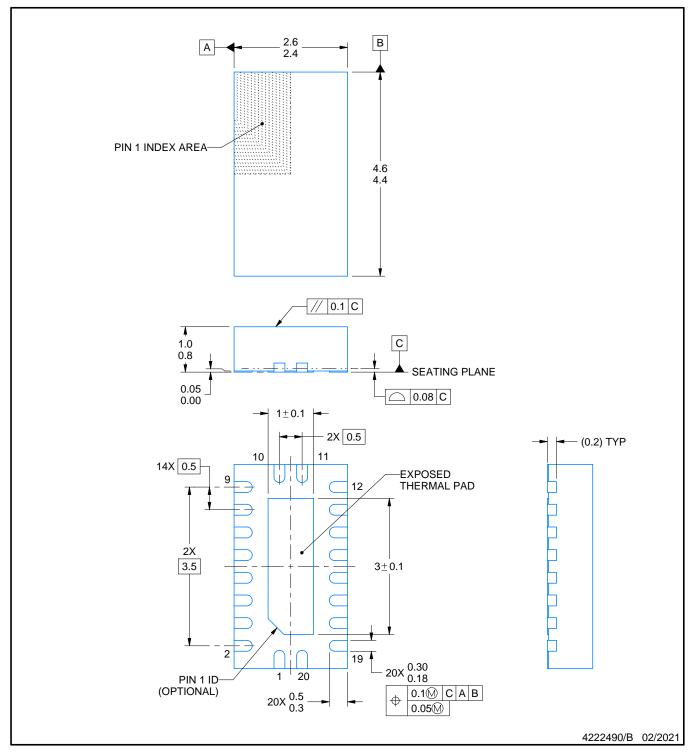
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLATPACK - NO LEAD

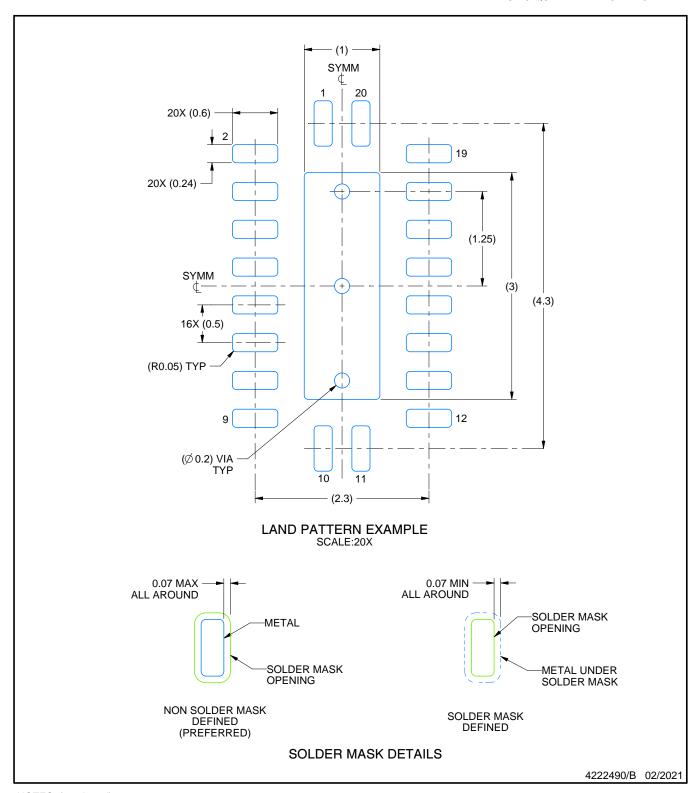


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

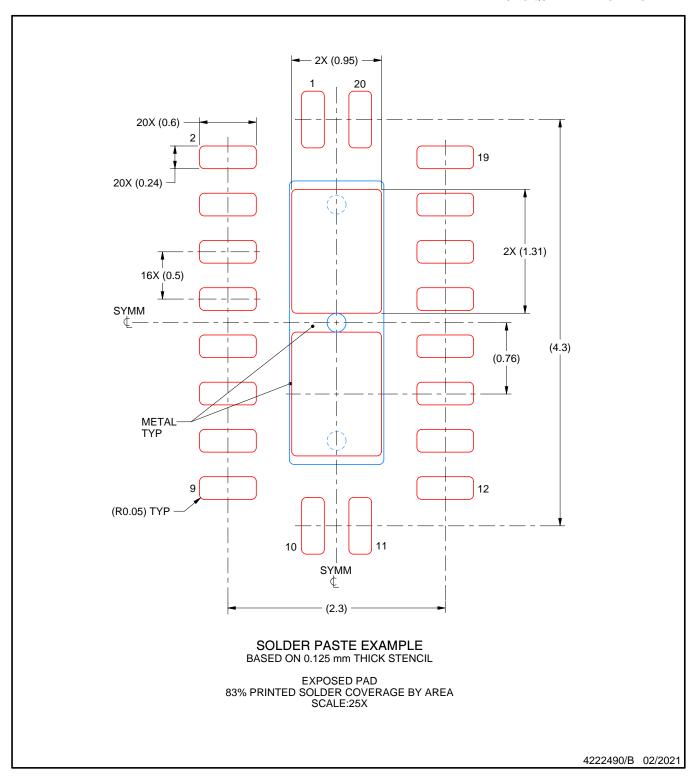


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If some or all are implemented, recommended via locations are shown.



PLASTIC QUAD FLATPACK - NO LEAD



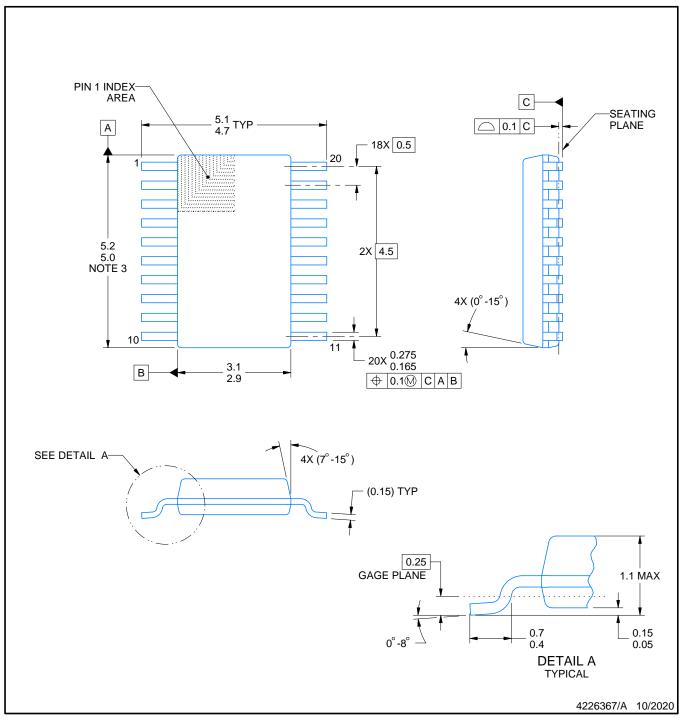
NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



NOTES:

PowerPAD is a trademark of Texas Instruments.

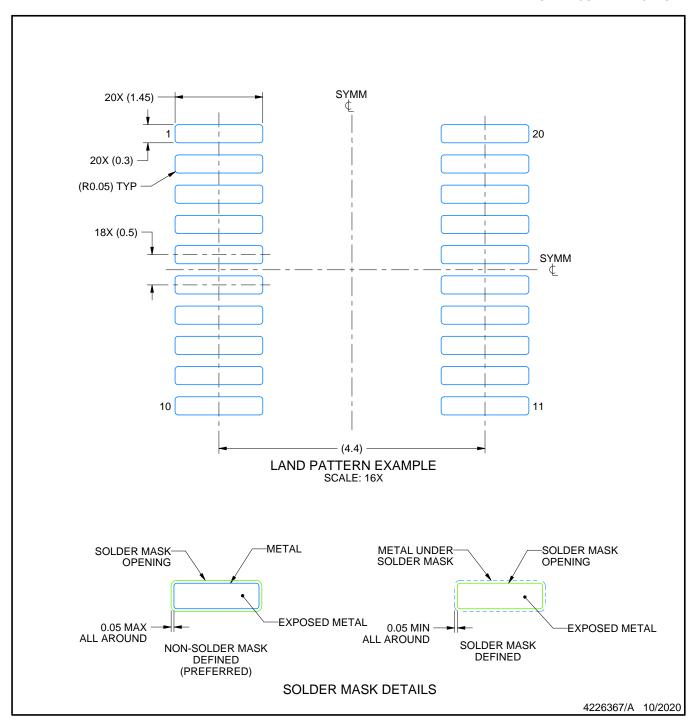
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. No JEDEC registration as of September 2020.
- 5. Features may differ or may not be present.



SMALL OUTLINE PACKAGE

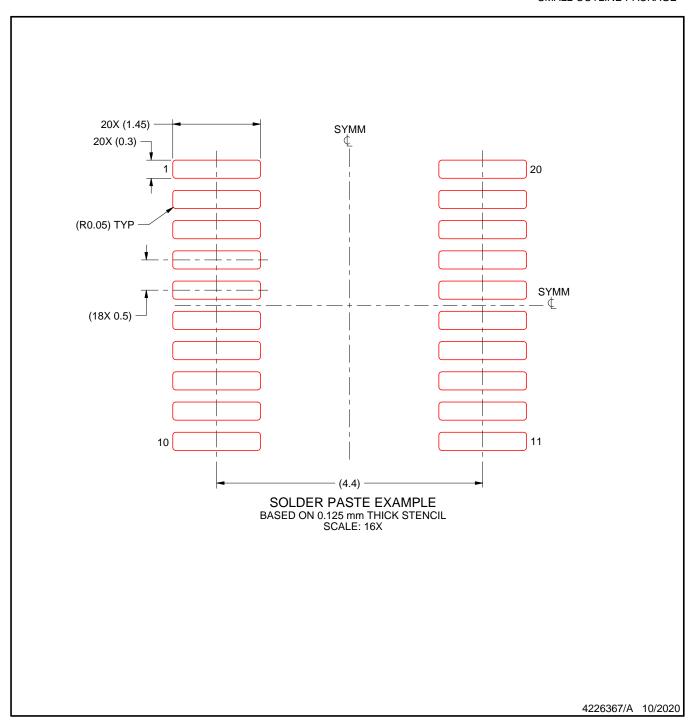


NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
- 9. Size of metal pad may vary due to creepage requirement.
- 10. Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.



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